

RELIABILITY REPORT





NOW PART OF



Reliability Data Report Product Family R562

LTC3613 \ LTC3815 \ LTC7138

Reliability Data Report

Report Number: R562

Report generated on: Mon Oct 23 17:33:56 PDT 2017

OPERATING LIFE TEST					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+125°C)¹	No. of FAILURES _{2, 3}
SSOP/TSSOP	77	1124	1124	257	0
SOIC/MSOP	77	1352	1352	257	0
QFN/DFN	231	1116	1431	411	0
Totals	385	-	-	925	0
PRESSURE COOKER TEST AT 15 PSIG , +121 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
SOIC/MSOP	50	1603	1603	1	0
QFN/DFN	399	1401	1709	9	0
Totals	449	-	-	10	0
TEMP CYCLE FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
SOIC/MSOP	50	1603	1603	5	0
QFN/DFN	541	1131	1709	325	0
Totals	591	-	-	330	0
THERMAL SHOCK FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
SOIC/MSOP	49	1603	1603	4	0
QFN/DFN	542	1131	1709	326	0
Totals	591	-	-	330	0
HIGH TEMPERATURE BAKE AT 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
QFN/DFN	50	1645	1645	50	0
Totals	50	-	-	50	0

(1) Assumes Activation Energy = 0.7 Electron Volts

(2) Failure Rate Equivalent to +55 °C, 60% Confidence Level =12.81 FITS

(3) Mean Time Between Failure in Years = 8911.56

Note: 1 FIT = 1 Failure in One Billion Hours.

Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 MSL1 Preconditioning